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The SEM equipment was mis-identified on this article [1]. The authors stated on the Method section that the the SEM images were obtained with a SU8010 model (Hitachi), however, the images show that they were obtained with a Regulus 8100 model.

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(XPS) was used to measure the charge states, electronic energy levels and compositions of CQDs/CO/PFO photocatalysts. A SU8010 field-emission scanning electron microscopy (FE-SEM) and JEM 2100F transmission electron microscopy (TEM) were used to observe the sur-

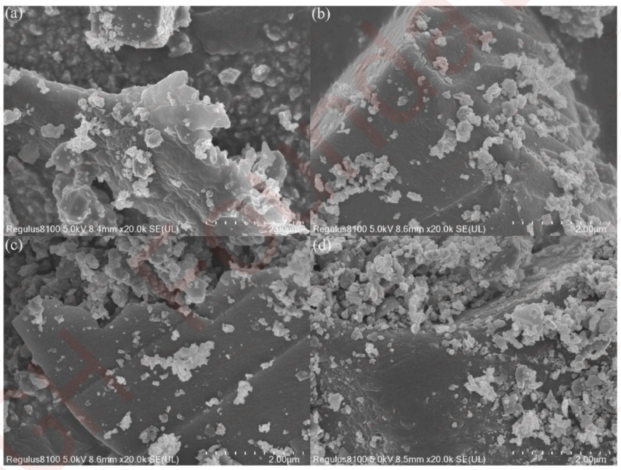

Fig. 4. FE-SEM photographs of CQDs/CO/PFO photocatalysts. (a) 3 mL-CQDs/CO/PFO, (b) 5 mL-CQDs/CO/PFO, (c) 7 mL-CQDs/CO/PFO, and (d) 9 mL-CQDs/CO/PFO.

The 5GH Team wants to address that misidentifying the SEM equipment does not necessarily suggest that the authors got involved in misconduct, but the authors from India (Navdeep Dhaliwal, Satbir S. Sehgal), and Saudi (Mohd Ubaidullah, Asad Syed) are questionable.

Article Information

Title: CQDs drives CeO2/PbFe12O19 photocatalysts for oxytetracycline hydrochloride removal by photoinduction and magnetic recovery

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